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- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Inputs Are TTL-Voltage Compatible
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

description

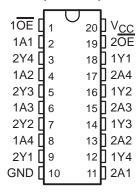
These octal buffers/drivers are designed specifically to improve both the performance and density of 3-state memory-address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 'AHCT244 devices are organized as two 4-bit buffers/line drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state

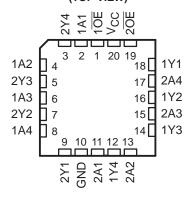
To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54AHCT244 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AHCT244 is characterized for operation from -40°C to 85°C.

SN54AHCT244 . . . J OR W PACKAGE SN74AHCT244 . . . DB, DGV, DW, N, OR PW PACKAGE (TOP VIEW)



SN54AHCT244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each 4-bit buffer/driver)

(00.011		,
INP	UTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	X	Z



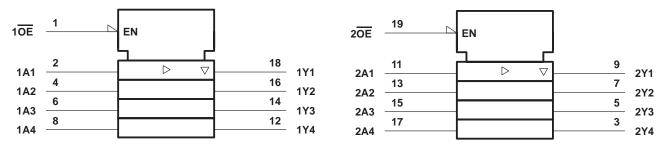
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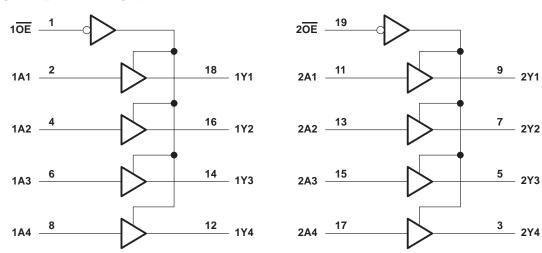
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Output voltage range, VO (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{ K }(V_{ I } < 0)$		
Output clamp current, IOK (VO < 0 or VO > VCO	c)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±25 mA
Continuous current through V _{CC} or GND		±75 mA
Package thermal impedance, θ _{JA} (see Note 2):	: DB package	70°C/W
	DGV package	92°C/W
	DW package	58°C/W
	N package	69°C/W
	PW package	83°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 3)

		SN54AHCT244		SN74AH	UNIT	
		MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
VIL	Low-level input voltage		0.8		0.8	V
٧ı	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0	VCC	0	VCC	V
loh	High-level output current		-8		-8	mA
loL	Low-level output current		8		8	mA
T _A	Operating free-air temperature	- 55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T _A = 25°C			SN54AHCT244		SN74AHCT244		UNIT
TAKAWETEK	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
VOH	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
	I _{OH} = -8 mA	4.5 V	3.94			3.8		3.8		V
Vai	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
VOL	I _{OL} = 8 mA	4.5 V			0.36		0.44		0.44	V
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.25		±2.5		±2.5	μΑ
l _l	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40		40	μΑ
ΔICC [†]	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5		1.5	mA
C _i	V _I = V _{CC} or GND	5 V		2.5	10				10	pF
Co	$V_O = V_{CC}$ or GND	5 V		3						pF



^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0 \text{ V}$. † This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC} .

SN54AHCT244, SN74AHCT244 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO LOAD		T _A	= 25°C	;	SN54AH	CT244	SN74AH	CT244	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
t _{PLH}	Α	Y	C _I = 15 pF		5.4*	7.4*	1*	8.5*	1	8.5	ns	
t _{PHL}	A	ı	CL = 13 pr		5.4*	7.4*	1*	8.5*	1	8.5	115	
t _{PZH}	ŌĒ	Y	C 15 pF		7.7*	10.4*	1*	12*	1	12	ns	
tPZL	OE	ī	C _L = 15 pF		7.7*	10.4*	1*	12*	1	12	115	
t _{PHZ}	ŌĒ	Y	C _L = 15 pF		5*	9.4*	1*	10*	1	10	ns	
t _{PLZ}		T T	CL = 15 pr		5*	9.4*	1*	10*	1	10	115	
t _{PLH}	А	Y	C: 50 pF		5.9	8.4	1	9.5	1	9.5		
tPHL	^	Ť	C _L = 50 pF		5.9	8.4	1	9.5	1	9.5	ns	
t _{PZH}	<u></u>	Y	C 50 pF		8.2	11.4	1	13	1	13	ns	
tPZL	ŌĒ	OE	ī	C _L = 50 pF		8.2	11.4	1	13	1	13	115
tPHZ	ŌĒ	Y	C. = 50 pE		8.8	11.4	1	13	1	13	ns	
t _{PLZ}		r	$C_L = 50 \text{ pF}$		8.8	11.4	1	13	1	13	115	
tsk(o)			C _L = 50 pF			1**				1	ns	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C (see Note 4)

PARAMETER		SN74AHCT244			UNIT
		MIN	TYP	MAX	ONII
V _{OH(V)}	Quiet output, minimum dynamic VOH		4.1		V
VIH(D)	High-level dynamic input voltage	2			V
V _{IL(D)}	Low-level dynamic input voltage			0.8	V

NOTE 4: Characteristics are for surface-mount packages only.

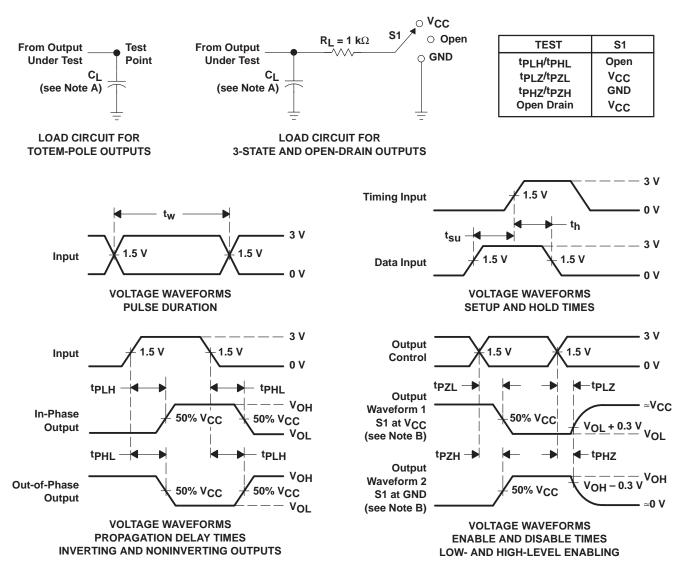
operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{nd} Power dissipation capacitance	No load, f = 1 MHz	8.2	pF



^{**} On products compliant to MIL-PRF-38535, this parameter does not apply.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 3 ns, $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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